

Notice of References Cited	Application/Control No. 10/779,379	Applicant(s)/Patent Under Reexamination CHAO, IWEN	
	Examiner Anh D. Mai	Art Unit 2814	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,975,764	12-1990	Hsu, Sheng T.	257/370
	B	US-5,204,541 A	04-1993	Smayling et al.	257/138
	C	US-5,198,689 A	03-1993	Fujioka, Hiroshi	257/197
	D	US-5,614,750 A	03-1997	Ellul et al.	257/386
	E	US-5,635,742	06-1997	Hoshi et al.	257/337
	F	US-5,939,755 A	08-1999	Takeuchi et al.	257/347
	G	US-6,225,674 B1	05-2001	Lim et al.	257/506
	H	US-6,242,787 B1	06-2001	Nakayama et al.	257/493
	I	US-6,831,331 B2	12-2004	Kitamura et al.	257/343
	J	US-2002/0066929 A1	06-2002	Voldman, Steven H.	257/355
	K	US-2003/0211701	11-2003	Desko et al.	438/424
	L	US-2004/0135141 A1	07-2004	Pequignot et al.	257/046
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-56-038835	04-1981	Japan	Nakajima et al.	H01L 21/76
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.